

Fig. 4

41; SEMICONDUCTOR TEST APPARATUS

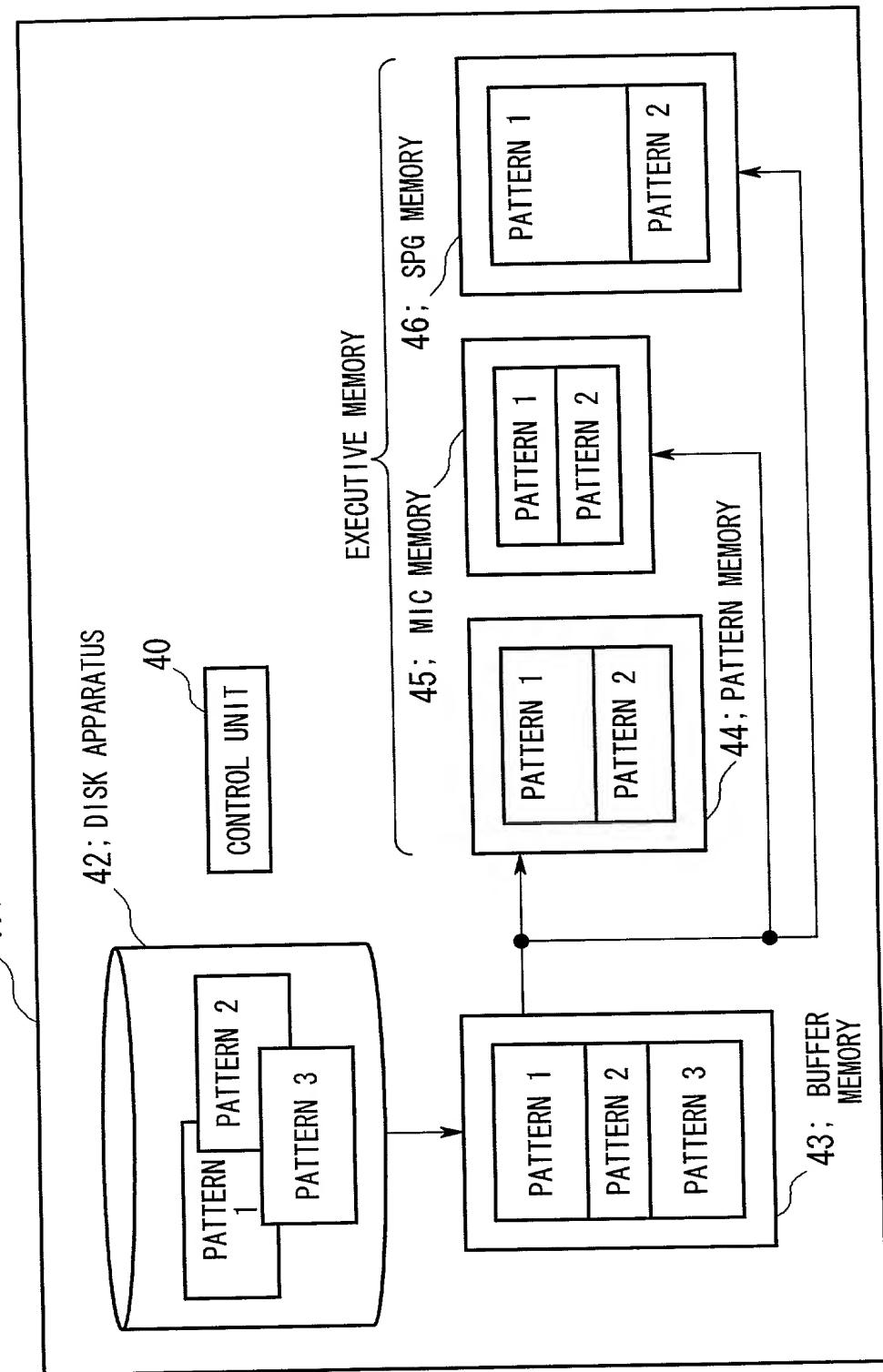


Fig. 5

